



Modular Automated Multi-Channel RF-Biased Burn-In Test Systems mitigating the risks of product failures in the field

The only integrated instrument that can demonstrate compliance with aerospace, government, and commercial RF semiconductor life test standards (GaAs, SiGe, GaN, SiC, InP and RFICs). Used by a majority of contractors participating in the DARPA wide-band-gap (WBG) semiconductor initiative and the follow-on Title III Program.